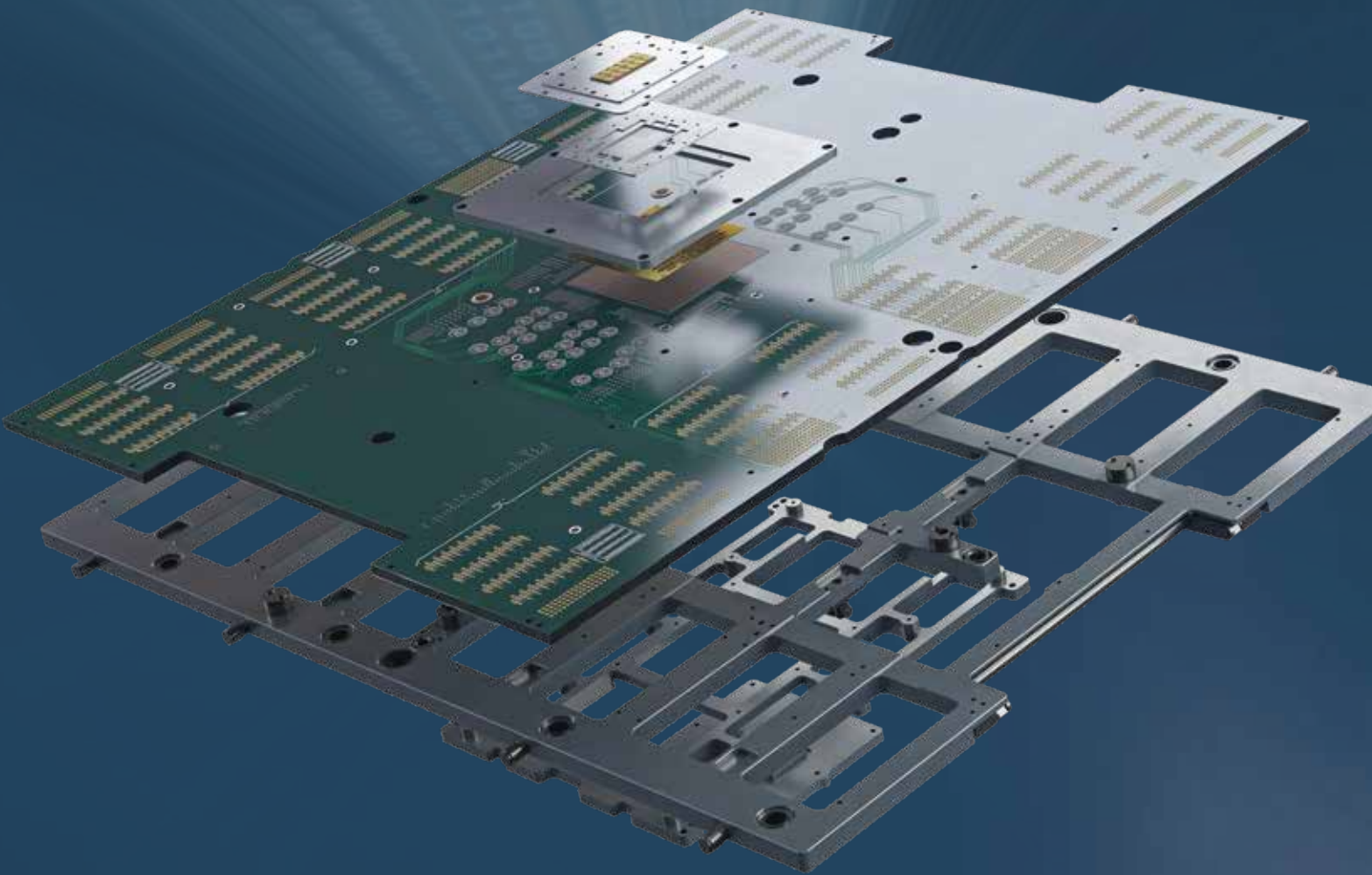


3D IC Probe Card Solution



Abuot CHPT

Chunghwa Precision Test Technology (CHPT; TPEX stock code 6510) was established in 2005, and originated from Chunghwa Telecom Laboratories. It is an unorthodox company in the semiconductor advanced test interface industry. By bringing together the talents from the fields of the mechanics, electronics, chemistry and optics, constructing an AI intelligent production and manufacturing environment, to strengthen its quality, cost, technology, delivery and service competitiveness. The unique fully vertically integrated approach or the “All in House” business model has successfully help its customers of all categories in the semiconductor industry to quickly innovate and develop for a win-win situation in the ever-changing technology industry.

Probe Needles

Specification	SR Series	BR Series	NS Series
Max. Pin Count	~20,000	~20,000	~50,000
Min. Pitch(um)	90	130~180	45~100
Temperature °C	-40~150	-40~150	-40~150
Probe Tip Type	Point/Flat	Point/Flat	Point/Flat



Global Locations

Taiwan

Taoyuan (Headquarters)
No.12, Gongye 3rd Rd., Pingzhen Dist., Taoyuan City 324, Taiwan
TEL: 886-3-469-1234
Hsinchu
Rm. 3C8 , 3F., No.1, Lixing 1st Rd., Hsinchu City 300, Taiwan
TEL: 886-3-577-9966
Taichung
1F., No. 356, Fuya Rd., Xitun Dist., Taichung City 407, Taiwan
TEL: 886-3-469-1234
Kaohsiung
NO.195, Tuku 1st RD., Nanzih District, Kaohsiung City 811, Taiwan
TEL: 886-7-353-2277

United States

California
2047 Zanker Road, Suite 10, San Jose, California, USA 95131
TEL: 1-408-380-0008

China

Suzhou
Room 101, Building 12, No. 200, Xingpu Road, Industrial Park, Suzhou, Jiangsu, China
TEL: 86-512-8916-2550
Shanghai
Room 802B, No.1000, Jinhai Rd., Building 16, Pudong New Area, Shanghai, China
TEL: 86-21-6089-1988

Japan

Tokyo
Asakawa Building 5th Floor, 2-1-17 Shiba Daimon, Minato-Ku, Tokyo 105-0012, Japan
TEL: 81-90-2564-4027



HIGH PERFORMANCE COMPUTING

High Temperature, High Pin Count Probe Card - Matching the Industry Trends.

To support the high performance computing segment, CHPT has newly launched BR and NS series probe cards with high temperature and high pin count that meet the testing requirements of various HPC chips.



HIGH SPEED / RADIO FREQUENCY

High Speed and RF Testing Solutions – Expected by the Markets.

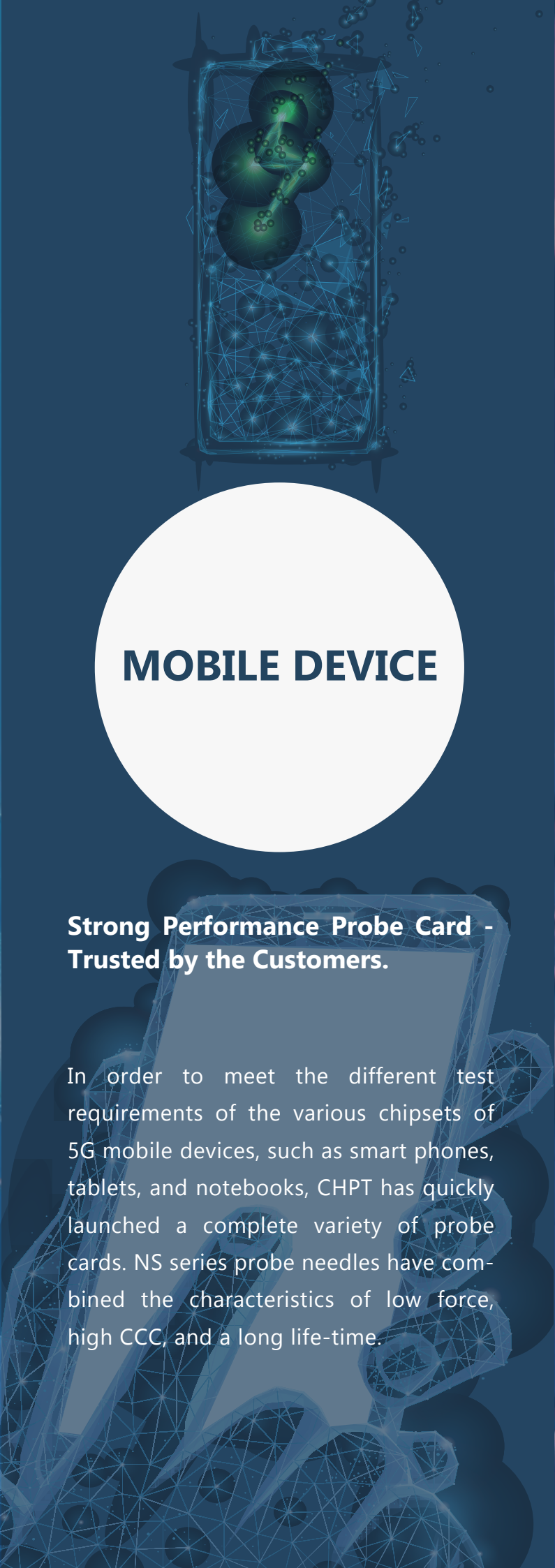


The 5G and AI era are coming. Mobile phones, wearable devices, and smart connectivity have increased the demand for high data transfer rates and greater bandwidth. CHPT offers the high speed and frequency test solutions, such as BK series probe cards.



MOBILE DEVICE

Strong Performance Probe Card - Trusted by the Customers.

In order to meet the different test requirements of the various chipsets of 5G mobile devices, such as smart phones, tablets, and notebooks, CHPT has quickly launched a complete variety of probe cards. NS series probe needles have combined the characteristics of low force, high CCC, and a long life-time.



MEMORY / CMOS IMAGE SENSOR

Stepped into Memory and CMOS Image Sensor - Meeting the Customer's Needs.

CHPT provides the complete and diverse product line for memory chip testing, including MJ series probe cards applicable in DRAM. In response to the number of chips required for automotive, drone and mobile phone camera, CHPT has also developed MJ series probe cards for CIS chip testing process.